Search Notes



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Reexamination 10550074 MUHONEN, JANNE MARKUS

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Applicant(s)/Patent Under

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SEARCHED

Class	Subclass	Date	Examiner
455	404.1-404.2, 445, 456.1-456.4, 422.1, 433, 461 text limited	12-18-2007	TTC
379	45, 37 text limited	12-18-2007	TTC
455	404.2	06-02-2008	TTC
455	404.1-404.2, 445, 456.1-456.4, 422.1, 433, 461 text limited (updated)	06-02-2008	TTC
379	45, 37 text limited (updated)	06-02-2008	TTC

SEARCH NOTES

Search Notes	Date	Examiner
PLUS Search considered by the examiner.	12-18-2007	TTC
Derwent	12-18-2007	TTC
EPO, JPO, IBM_TDB	12-19-2007	TTC
ACM, IEEE, ProQuest (NPL)	12-19-2007	TTC
EAST Search history attached	12-27-2007	TTC
Derwent (updated)	06-02-2008	TTC
EPO/JPO (updated)	06-02-2008	TTC
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INTERFERENCE SEARCH

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